

# Self Protected High Side Driver with Temperature Shutdown and Current Limit NCV8460A

The NCV8460A is a fully protected High–Side driver that can be used to switch a wide variety of loads, such as bulbs, solenoids and other acuators. The device is internally protected from an overload condition by an active current limit and thermal shutdown.

A diagnostic output reports ON and OFF state open load conditions as well as thermal shutdown.

#### **Features**

- Short Circuit Protection
- Thermal Shutdown with Automatic Restart
- CMOS compatible control input
- Open Load Detection in On and Off State
- Diagnostic Output
- Undervoltage and Overvoltage Shutdown
- Loss of Ground Protection
- ESD protection
- Slew Rate Control for Low EMI Switching
- Very Low Standby Current
- NCV Prefix for Automotive and Other Applications Requiring Unique Site and Control Change Requirements; AEC Qualified and PPAP Capable
- These Devices are Pb-Free and are RoHS Compliant

### **Typical Applications**

- Switch a Variety of Resistive, Inductive and Capacitive Loads
- Can Replace Electromechanical Relays and Discrete Circuits
- Automotive / Industrial

#### PRODUCT SUMMARY

Parameter	Symbol	Value	Units
Operating Voltage Range	V <sub>S</sub>	6 to 36	V
$R_{DSon(max)} T_J = 25^{\circ}C$	R <sub>ON</sub>	60	mΩ
Output Current Limit (min)	I <sub>lim</sub>	6	Α

#### MARKING DIAGRAM



SO-8 D SUFFIX CASE 751

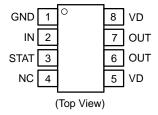


V8460A = Specific Device Code

A = Assembly Location

L = Wafer Lot
Y = Year
W = Work Week
Pb-Free Package

#### **PIN CONNECTIONS**



#### ORDERING INFORMATION

Device	Package	Shipping <sup>†</sup>
NCV8460ADR2G	SOIC-8 (Pb-Free)	2500 / Tape & Reel

<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

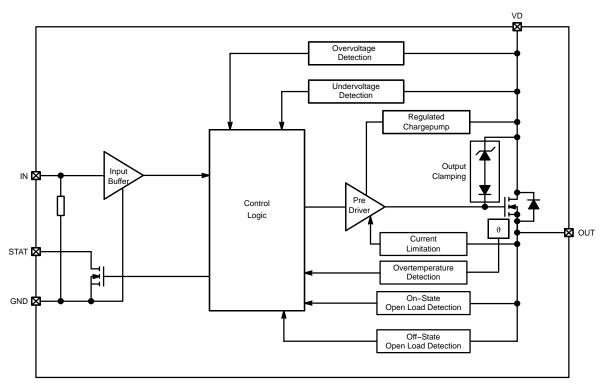


Figure 1. Block Diagram

### **PIN DESCRIPTION**

Pin#	Symbol	Description
1	GND	Ground
2	IN	Logic Level Input
3	STAT	Status Output
4	N/C	No Connection
5	$V_{D}$	Supply Voltage
6	OUT	Output
7	OUT	Output
8	$V_{D}$	Supply Voltage

#### **MAXIMUM RATINGS**

		Va		
Rating	Symbol	Min	Max	Unit
DC Supply Voltage	V <sub>D</sub>	-0.3	41	V
Peak Transient Input Voltage (Load Dump 42.5 V, $V_D$ = 13.5 V, $R_{LOAD}$ = 6.5 $\Omega$ , ISO7637–2 pulse 5)	$V_{ m peak}$		56	V
Input Voltage	V <sub>in</sub>	-8	8	V
Input Current	I <sub>in</sub>	-5	5	mA
Output Current (Note 1)	l <sub>out</sub>	-6	Internally Limited	Α
Negative Ground Current	-I <sub>gnd</sub>	-200	_	mA
Status Current	I <sub>status</sub>	-5	5	mA
Power Dissipation, T <sub>A</sub> = 25°C	P <sub>tot</sub>	1.	183	W
Electrostatic Discharge (HBM Model 100 pF / 1500 Ω) Input Status Output V <sub>D</sub>		4 3.5 5 5		DC kV kV kV
Single Pulse Inductive Load Switching Energy (Note 2) (L = 1.8 mH, $V_{bat}$ = 13.5 V; $I_L$ = 9 A, $T_{Jstart}$ = 150°C)	E <sub>AS</sub>	100		mJ
Operating Junction Temperature	TJ	-40	+150	°C
Storage Temperature	T <sub>storage</sub>	-55	+150	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

1. Reverse Output current has to be limited by the load to stay within absolute maximum ratings and thermal performance.

#### THERMAL RESISTANCE RATINGS

Parameter	Symbol	Max Value	Unit
Thermal Resistance Junction-to-Lead	$R_{ hetaJL}$	30	°C/W
Junction-to-Ambient (min. Pad) Junction-to-Ambient (1" square pad size, FR-4, 1 oz Cu)	$R_{ hetaJA}^{odL} \ R_{ hetaJA}$	110.8 105.6	°C/W °C/W

<sup>2.</sup> Not subjected to production testing.

## **ELECTRICAL CHARACTERISTICS** (8 $\leq$ V<sub>D</sub> $\leq$ 36 V; $-40^{\circ}$ C < T<sub>J</sub> < 150 $^{\circ}$ C unless otherwise specified)

			Value			
Rating	Symbol	Conditions	Min	Тур	Max	Unit
Operating Supply Voltage	$V_{D}$		6	-	36	V
Undervoltage Shutdown	V <sub>UV</sub>		3	5	6	V
Undervoltage	V <sub>UV_Rst</sub>				6.5	V
Overvoltage Shutdown	V <sub>OV</sub>		36			V
On Resistance	R <sub>ON</sub>	$I_{out} = 2 \text{ A}; T_J = 25^{\circ}\text{C}, V_D > 8 \text{ V}$ $I_{out} = 2 \text{ A}, V_D > 8 \text{ V}$			60 120	mΩ
Standby Current	I <sub>D</sub>	Off State, $V_{in} = V_{out} = 0 \text{ V}, V_D = 13.5 \text{ V}$ On State; $V_{in} = 5 \text{ V}, V_D = 13.5 \text{ V}, I_{out} = 0 \text{ A}$		10 1.5	20 3.5	μA mA
Output Leakage Current	Ι <sub>L</sub>	$V_{in} = V_{out} = 0 \text{ V}$ $V_{in} = 0 \text{ V}, V_{out} = 3.5 \text{ V}$ $V_{in} = V_{out} = 0 \text{ V}, V_D = 13.5 \text{ V}$	-20		50 10 3	μΑ
INPUT CHARACTERISTICS						
Input Voltage - Low	V <sub>in_low</sub>				1.25	V
Input Current – Low	I <sub>in_low</sub>	V <sub>in</sub> = 1.25 V	1			μΑ
Input Voltage – High	V <sub>in_high</sub>		3.25			V
Input Current – High	I <sub>in_high</sub>	V <sub>in</sub> = 3.25 V			10	μΑ
Input Hysteresis Voltage	V <sub>hyst</sub>		0.25			V
Input Clamp Voltage	V <sub>in_cl</sub>	I <sub>in</sub> = 1 mA I <sub>in</sub> = -1 mA	11 –13	12 –12	13 –11	V
SWITCHING CHARACTERISTI	cs					
Turn-On Delay Time	t <sub>d_on</sub>	to 10% $V_{out}$ , $V_D$ = 13.5 $V$ , $R_L$ = 6.5 $\Omega$		40		μs
Turn-Off Delay Time	t <sub>d_off</sub>	to 90% $V_{out}$ , $V_D$ = 13.5 $V$ , $R_L$ = 6.5 $\Omega$		30		μs
Slew Rate On	dV <sub>out</sub> / dt <sub>on</sub>	10% to 80% $V_{out}$ , $V_D$ = 13.5 V, $R_L$ = 6.5 $\Omega$		0.9		V / μs
Slew Rate Off	dV <sub>out</sub> / dt <sub>off</sub>	90% to 10% $V_{out}$ , $V_D$ = 13.5 V, $R_L$ = 6.5 $\Omega$		0.7		V / μs
OUTPUT DIODE CHARACTER	ISTICS (Note 3)					
Forward Voltage	V <sub>F</sub>	$I_{out} = -1.3 \text{ A}, T_J = 150^{\circ}\text{C}$			0.6	V
STATUS PIN CHARACTERISTI	CS					
Status Output Voltage Low	V <sub>stat_low</sub>	I <sub>stat</sub> = 1.6 mA		0.2	0.5	V
Status Leakage Current	I <sub>stat_leakage</sub>	V <sub>stat</sub> = 5 V		1	10	μΑ
Status Pin Input Capacitance	C <sub>stat</sub>	V <sub>stat</sub> = 5 V (Note 3)			100	pF
Status Clamp Voltage	V <sub>stat_cl</sub>	I <sub>stat</sub> =1 mA I <sub>stat</sub> = -1 mA	10 –2.2	11 –1.2	12 -0.6	V
PROTECTION FUNCTIONS (No	ote 4)					
Temperature Shutdown (Note 3)	T <sub>SD</sub>		150	175	200	°C
Temperature Shutdown Hysteresis (Note 3)	T <sub>SD_hyst</sub>		7	15		°C
Output Current Limit	I <sub>lim</sub>	8 V < V <sub>D</sub> < 36 V	6	9	15	Α
		6 V < V <sub>D</sub> < 36 V			15	Α
Status Delay in Overload	t <sub>d_stat</sub>				20	μs
Switch Off Output Clamp Voltage	V <sub>clamp</sub>	$I_{out} = 2 \text{ A}, V_{in} = 0 \text{ V}, L = 6 \text{ mH}$	V <sub>D</sub> – 41	V <sub>D</sub> – 45	V <sub>D</sub> – 55	V

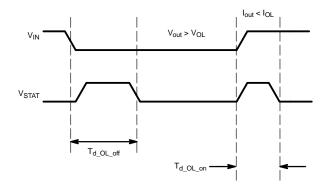
Not subjected to production testing
 To ensure long term reliability under heavy overload or short circuit conditions, protection and related diagnostic signals must be used together with a proper hardware/software strategy. If the devices operates under abnormal conditions this hardware/software solutions must limit the duration and number of activation cycles.

**ELECTRICAL CHARACTERISTICS** ( $8 \le V_D \le 36 \text{ V}$ ;  $-40^{\circ}\text{C} < T_J < 150^{\circ}\text{C}$  unless otherwise specified)

				Value		
Rating	Symbol	Conditions	Min	Тур	Max	Unit
DIAGNOSTICS CHARACTERIST	гісѕ					
Openload On State Detection Threshold	l <sub>OL</sub>	V <sub>in</sub> = 5 V	30		500	mA
Openload On State Detection Delay	t <sub>d_OL_on</sub>	I <sub>out</sub> = 0 A			220	μS
Openload Off State Detection Threshold	V <sub>OL</sub>	V <sub>in</sub> = 0 V	1.5	_	3.5	V
Openload Detection Delay at Turn Off	t <sub>d_OL_off</sub>				1000	μs

- 3. Not subjected to production testing
- 4. To ensure long term reliability under heavy overload or short circuit conditions, protection and related diagnostic signals must be used together with a proper hardware/software strategy. If the devices operates under abnormal conditions this hardware/software solutions must limit the duration and number of activation cycles.

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.



 $V_{IN}$   $T_{J} > T_{J\_TSD}$   $T_{d\_STAT}$   $T_{d\_STAT}$ 

Figure 2. Open Load Status Timing (with external pull-up)

Figure 3. Overtemperature Status Timing

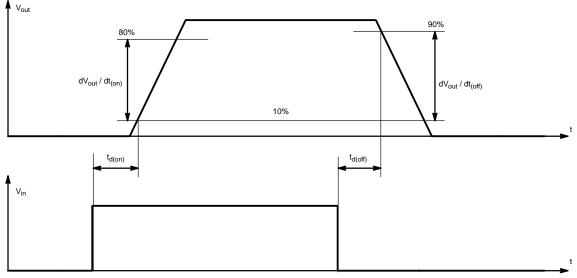
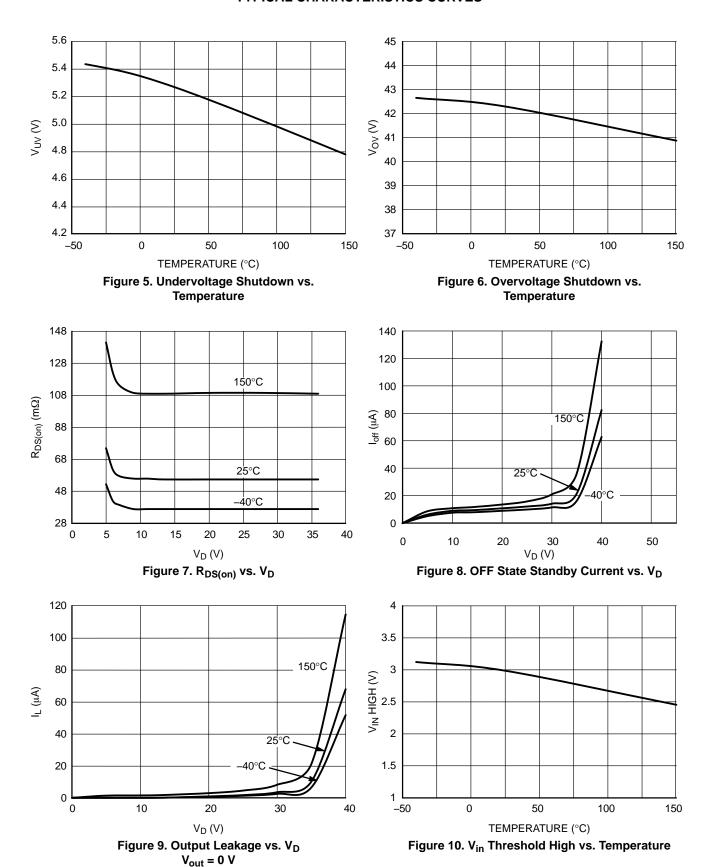


Figure 4. Switching Timing Diagram

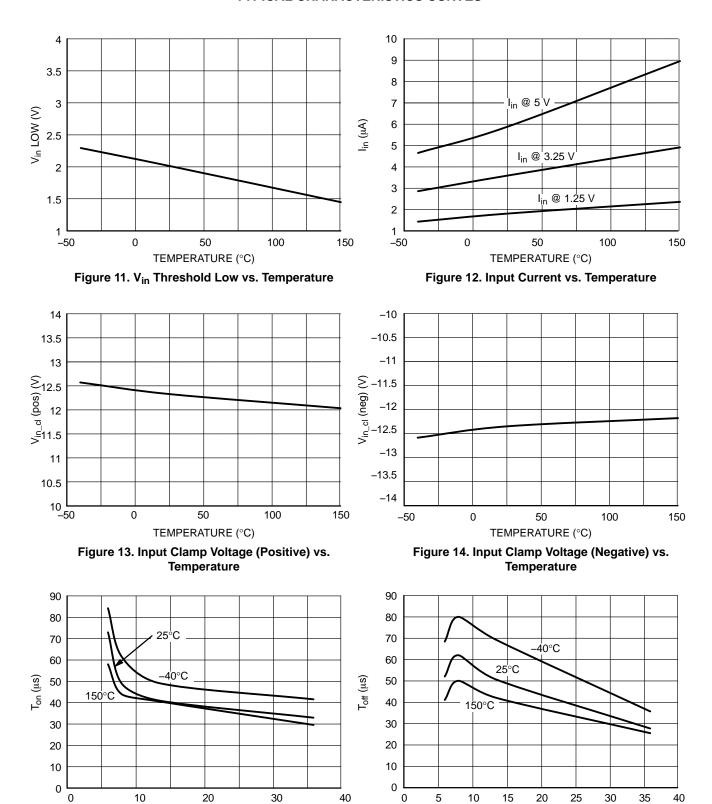
### **STATUS PIN TRUTH TABLE**

Conditions	Input	Output	Status
Normal Operation	L	L	H
	H	H	H
Undervoltage	L	L	X
	H	L	X
Overvoltage	L	L	H
	H	L	H
Current Limitation	L	L	H
	H	X	(T <sub>J</sub> < T <sub>SD</sub> ) H
	H	X	(T <sub>J</sub> > T <sub>SD</sub> ) L
Overtemperature	L	L	H
	H	L	L
Output Voltage > V <sub>OL</sub>	L	H	L
	H	H	H
Output Current < I <sub>OL</sub>	L	L	H
	H	H	L

#### **TYPICAL CHARACTERISTICS CURVES**



#### **TYPICAL CHARACTERISTICS CURVES**



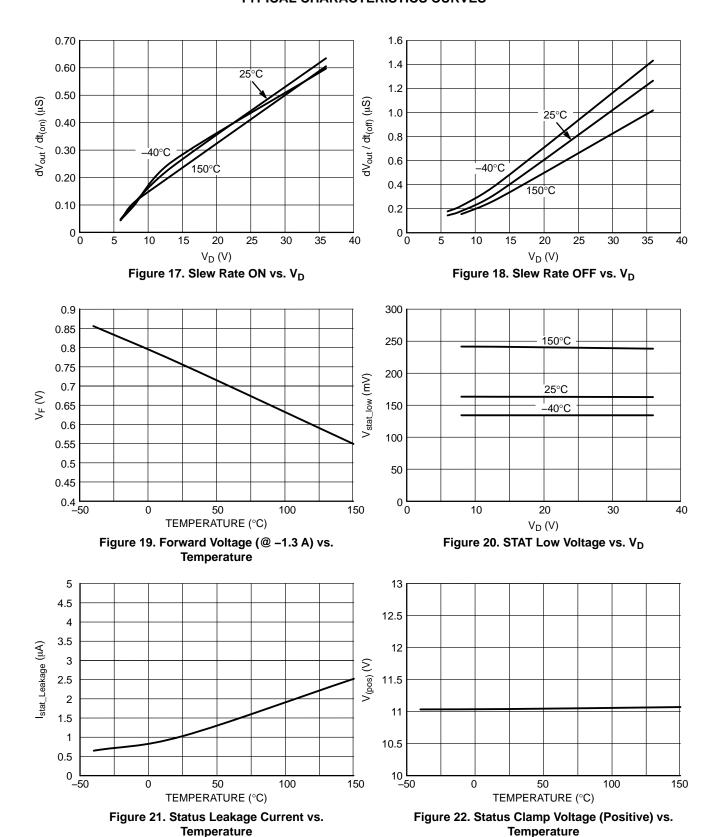
 $V_D(V)$ 

Figure 16. Turn Off Time vs. V<sub>D</sub>

 $V_D(V)$ 

Figure 15. Turn On Time vs. V<sub>D</sub>

#### **TYPICAL CHARACTERISTICS CURVES**



#### **TYPICAL CHARACTERISTICS CURVES**

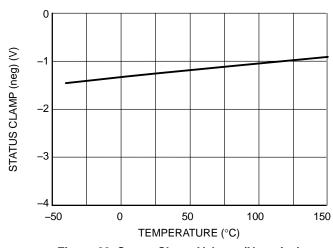


Figure 23. Status Clamp Voltage (Negative) vs. Temperature

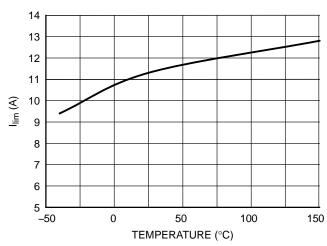


Figure 24. Current Limit vs. Temperature  $V_D = 13.5 \text{ V}$ 

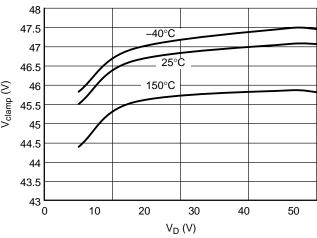


Figure 25. Turn Off Output Clamp Voltage vs.  $V_{\mbox{\scriptsize D}}$  and Temperature

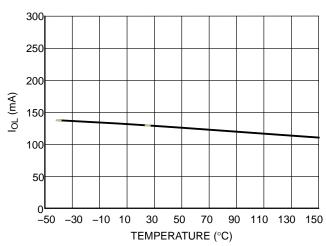


Figure 26. ON State Open Load Detection vs. Temperature  $V_D = 13.5 \text{ V}$ 

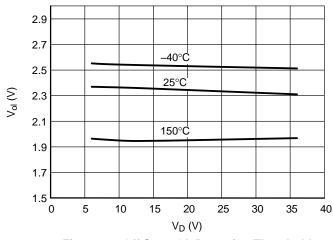


Figure 27. Off State OL Detection Threshold vs.  $V_D$  and Temperature

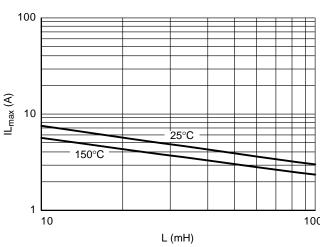


Figure 28. Single-Pulse Maximum Switch-off Current vs. Load Inductance

### **TYPICAL CHARACTERISTICS CURVES**

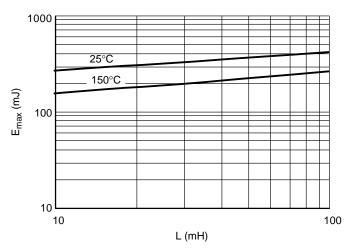


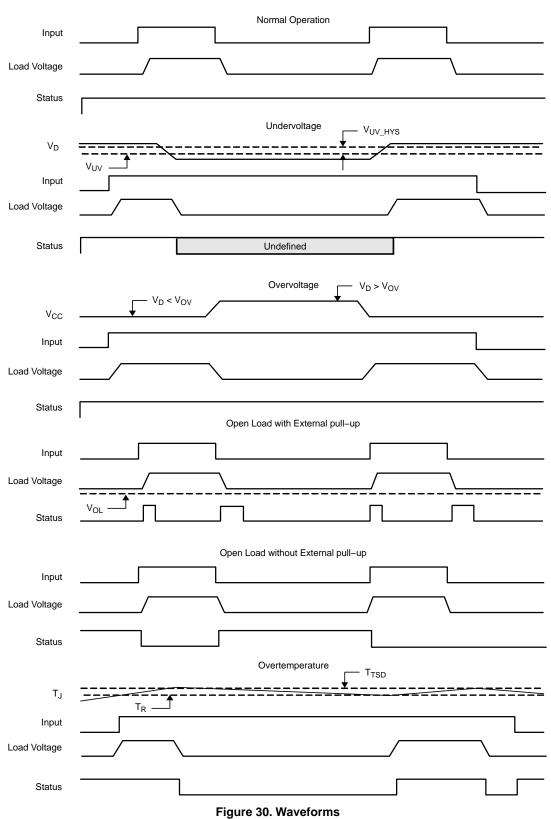
Figure 29. Single-Pulse Maximum Switch-off Current vs. Load Inductance

### ISO 7637-2: 2004(E) PULSE TEST RESULTS

ISO 7637-2:2004(E)		Test Levels			
Test Pulse	I	II	III	IV	Impedance
1	–25 V	–50 V	–75 V	–100 V	2 ms, 10 Ω
2a	+25 V	+50 V	+37 V	+50 V	0.05 ms, 10 $\Omega$
3a	–25 V	–50 V	–112 V	–150 V	0.1 μs, 50 Ω
3b	+25 V	+50 V	+75 V	+100 V	0.1 μs, 50 Ω
4	-4 V	−5 V	−6 V	-7 V	5 s, .01 Ω
5 (Load Dump)	+26.5 V	+46.5 V	+66.5 V	+86.5 V	400 ms, 2 $\Omega$

ISO 7637-2:2004(E)	Test Results			
Test Pulse	1	II	III	IV
1	С	С	С	С
2a	С	С	С	С
3a	С	С	С	С
3b	С	С	С	С
4	С	С	С	С
5 (Load Dump)	С	E	E	E

Class	Functional Status
А	All functions of a device perform as designed during and after exposure to disturbance.
В	All functions of a device perform as designed during exposure. However, one or more of
	them can go beyond specified tolerance. All functions return automatically to within normal
	limits after exposure is removed. Memory functions shall remain class A.
С	One or more functions of a device do not perform as designed during exposure but return
	automatically to normal operation after exposure is removed.
D	One or more functions of a device do not perform as designed during exposure and do not return to normal operation until exposure is removed and the device is reset by simple
E	One or more functions of a device do not perform as designed during and after exposure and cannot be returned to proper operation without replacing the device.



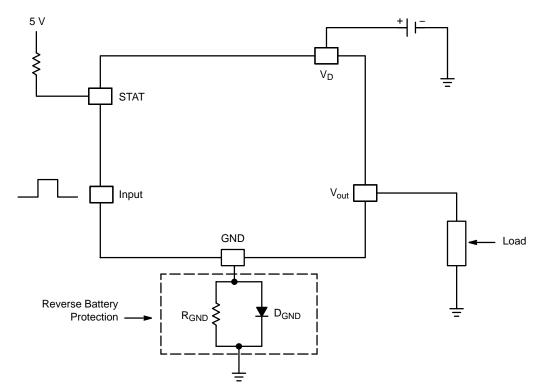


Figure 31. Application Diagram

#### **Reverse Battery Protection**

An external resistor  $R_{GND}$  is required to adequately protect the device from a Reverse Battery event. The resistor value can be calculated using the following two formulas.

- 1.  $R_{GND} \le 600 \text{ mV} / (I_d \text{ (on) max})$
- 2.  $R_{GND} \ge (-V_D) / (-I_{gnd})$

Maximum (- $I_{gnd}$ ) current, which is the reverse GND pin current, can be found in the Maximum Ratings section. Several High Side Devices can share same the reverse battery protection resistor. Please note that the sum of ( $I_d$  (on) max) of all devices should be used to calculate  $R_{GND}$  value. If the microprocessor ground is not common with the device ground,  $R_{GND}$  will produce a voltage offset (( $I_d$  (on) max) x  $R_{GND}$ ) with respect to the IN and STAT pins.

This offset will be increased when more than one device shares the resistor.

Power Dissipation during a reverse battery event is equal to:

$$P_{D} = \left(-V_{D}\right)^{2} / R_{GND}$$

In the case of high power dissipation due to several devices sharing  $R_{GND}$ , it is recommended to place a diode  $D_{GND}$  in the ground path as an alternate reverse battery protection method. When driving an inductive load, a 1  $k\Omega$  resistor should be placed in parallel with the  $D_{GND}$  diode. This method will also produce a voltage offset of ~600 mV with respect to the IN and STAT pins. This diode can also be shared amongst several High Side Devices. This voltage offset will vary if  $D_{GND}$  is shared by multiple devices.

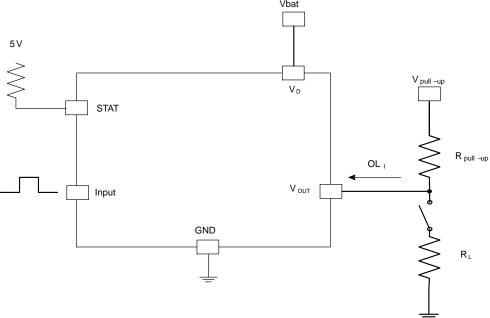


Figure 32. Open Load Detection In Off State

#### **OFF State Open Load Detection**

Off State Open Load Detection requires an external pull-up resistor ( $R_{pull-up}$ ) connected between  $V_{OUT}$  pin and a positive supply voltage ( $V_{pull-up}$ ).

The external  $R_{pull-up}$  resistor value should be selected to ensure that a false OFF State OL condition is not detected when the load  $(R_L)$  is connected. A  $V_{OUT}$  voltage above the  $V_{OL\_min}$  (Openload Off State Detection Threshold) minimum value with the load  $(R_L)$  connected needs to be avoided. The following formula shows this relationship:

$$V_{OUT} = \left(V_{pull-up}/\left(R_L + R_{pull-up}\right)\right)R_L < V_{OL\_min}$$

In addition to ensuring the selected  $R_{pull-up}$  resistor value does not cause a false OFF State OL detection condition

when the load is connected, the  $R_{pull-up}$  must also not cause the OFF State OL to miss detecting an OL condition when the load is disconnected. A  $V_{OUT}$  voltage below the  $V_{OL\_max}$  (Openload Off State Detection Threshold) maximum value with the load ( $R_L$ ) disconnected needs to be avoided. The following formula shows this relationship:

$$R_{pull-up} < (V_{pull-up} - V_{OL\ max})/OL_1$$

$$OL_1 = I_1 (Output Leakage with V_{OUT} = 3.5 V)$$

Because  $I_d$  (OFF) may significantly increase if  $V_{OUT}$  is pulled high (up to several mA),  $R_{pull-up}$  resistor should be connected to a supply that is switched OFF when the module is in standby.

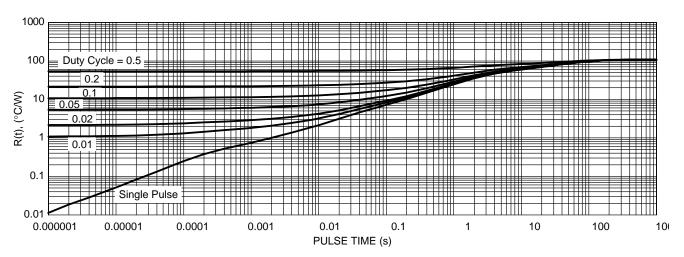


Figure 33. Transient Thermal Impedance

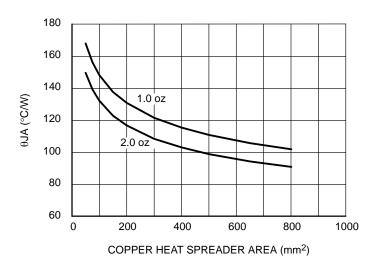


Figure 34.  $R_{\theta JA}$  vs Copper Area



SOIC-8 NB CASE 751-07 **ISSUE AK** 

**DATE 16 FEB 2011** 



- NOTES:
  1. DIMENSIONING AND TOLERANCING PER
- ANSI Y14.5M, 1982.
  CONTROLLING DIMENSION: MILLIMETER.
- DIMENSION A AND B DO NOT INCLUDE MOLD PROTRUSION.
- MAXIMUM MOLD PROTRUSION 0.15 (0.006) PER SIDE
- DIMENSION D DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION SHALL BE 0.127 (0.005) TOTAL IN EXCESS OF THE D DIMENSION AT MAXIMUM MATERIAL CONDITION.
- 751-01 THRU 751-06 ARE OBSOLETE. NEW STANDARD IS 751-07.

	MILLIMETERS		INC	HES	
DIM	MIN	MAX	MIN	MAX	
Α	4.80	5.00	0.189	0.197	
В	3.80	4.00	0.150	0.157	
С	1.35	1.75	0.053	0.069	
D	0.33	0.51	0.013	0.020	
G	1.27	7 BSC	0.050 BSC		
Н	0.10	0.25	0.004	0.010	
J	0.19	0.25	0.007	0.010	
K	0.40	1.27	0.016	0.050	
М	0 °	8 °	0 °	8 °	
N	0.25	0.50	0.010	0.020	
S	5.80	6.20	0.228	0.244	

#### **SOLDERING FOOTPRINT\***



<sup>\*</sup>For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

#### **GENERIC MARKING DIAGRAM\***



XXXXX = Specific Device Code = Assembly Location

= Wafer Lot = Year = Work Week

= Pb-Free Package



XXXXXX = Specific Device Code = Assembly Location Α

= Year ww = Work Week

= Pb-Free Package

\*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot "•", may or may not be present. Some products may not follow the Generic Marking.

#### **STYLES ON PAGE 2**

DOCUMENT NUMBER:	98ASB42564B	Electronic versions are uncontrolled except when accessed directly from the Document Repository. Printed versions are uncontrolled except when stamped "CONTROLLED COPY" in red.	
DESCRIPTION:	SOIC-8 NB		PAGE 1 OF 2

ON Semiconductor and un are trademarks of Semiconductor Components Industries, LLC dba ON Semiconductor or its subsidiaries in the United States and/or other countries. ON Semiconductor reserves the right to make changes without further notice to any products herein. ON Semiconductor makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does ON Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. ON Semiconductor does not convey any license under its patent rights nor the rights of others.

#### SOIC-8 NB CASE 751-07 ISSUE AK

### DATE 16 FEB 2011

STYLE 4: PIN 1. ANODE 1 2. ANODE 2 3. ANODE 2 4. ANODE 5. ANODE #2 6. ANODE #2 7. ANODE #1 8. COMMON CATHODE
STYLE 8: PIN 1. COLLECTOR, DIE #1 2. BASE, #1 3. BASE, #2 4. COLLECTOR, #2 5. COLLECTOR, #2 6. EMITTER, #2 STAGE Vd 7. EMITTER, #1 AGE Vd 8. COLLECTOR, #1
STYLE 12:  1 PIN 1. SOURCE 2 SOURCE 2 3. SOURCE 4. GATE 5. DRAIN 6. DRAIN 7. DRAIN 8. DRAIN
STYLE 16: PIN 1. EMITTER, DIE #1 2. BASE, DIE #1 3. EMITTER, DIE #2 4. BASE, DIE #2 5. COLLECTOR, DIE #2 6. COMMON 6. COLLECTOR, DIE #2 6. COMMON 7. COLLECTOR, DIE #1 6. COMMON 8. COLLECTOR, DIE #1
STYLE 20:  1 PIN 1. SOURCE (N) 2. GATE (N) 2 3. SOURCE (P) 4. GATE (P) 5. DRAIN 2 6. DRAIN 7. DRAIN 1 8. DRAIN
STYLE 24:   PIN 1. BASE     N ANODE/GND   2. EMITTER     N ANODE/GND   3. COLLECTOR/ANODE     UT   5. CATHODE     N ANODE/GND   6. CATHODE     N ANODE/GND   7. COLLECTOR/ANODE     UT   8. COLLECTOR/ANODE
STYLE 28: PIN 1. SW_TO_GND 2. DASIC_OFF 3. DASIC_SW_DET 4. GND E 5. V_MON E 6. VBULK E 7. VBULK 8. VIN

DOCUMENT NUMBER:	98ASB42564B	Printed versions are uncontrolled except when stamped "CONTROLLED COPY" in red.	
DESCRIPTION:	SOIC-8 NB		PAGE 2 OF 2

ON Semiconductor and IN are trademarks of Semiconductor Components Industries, LLC dba ON Semiconductor or its subsidiaries in the United States and/or other countries. ON Semiconductor reserves the right to make changes without further notice to any products herein. ON Semiconductor makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does ON Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. ON Semiconductor does not convey any license under its patent rights nor the rights of others.